

Automatic test generation system for VLSI

Jervan, Gert; Markus, Antti; Raik, Jaan; Ubar, Raimund-Johannes Proceedings of the First Electronic Circuits and Systems Conference : Bratislava, Slovakia, September 4-5, 1997 1997 / p. 255-258

Fast modelling of oscillator transients

Kukk, Vello Proceedings of the First Electronic Circuits and Systems Conference : Bratislava, Slovakia, September 4-5, 1997 1997 / p. 27-30: ill

High-Q active bandpass filters

Õöpik, Priit; Koort, Marko; Kipper, Rein; **Kukk, Vello** Proceedings of the First Electronic Circuits and Systems Conference : Bratislava, Slovakia, September 4-5, 1997 1997 / p. 133-136: ill

Interactive synthesiser development

Koort, Marko; Kukk, Vello Proceedings of the First Electronic Circuits and Systems Conference : Bratislava, Slovakia, September 4-5, 1997 1997 / p. 67-70 : ill

Representing transparency conditions in test generation for VLSI by decision diagrams

Ubar, Raimund-Johannes Proceedings of the First Electronic Circuits and Systems Conference : Bratislava, Slovakia, September 4-5, 1997 1997 / p. 213-216